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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**In re patent application of**

Keizo Yamada

**Serial No.:** 09/865,528

**Group Art Unit:** 2829

**Filed:** May 29, 2001

**Examiner:** Nguyen, Vinh P.

**For:** SEMICONDUCTOR DEVICE TEST METHOD AND SEMICONDUCTOR DEVICE  
TESTER

Honorable Commissioner of Patents  
Alexandria, VA 22313 - 1450

**AMENDMENT UNDER 37 C.F.R. §1.111**

Sir:

In response to the Office Action dated June 4, 2003, please amend the above-identified application as follows:

**INTRODUCTORY COMMENTS**

Claims 1-26 are all the claims presently pending in the application. Claims 1, 14 and 26 have been amended to more clearly define the invention. Claims 2-13 and 15-25 have been withdrawn from prosecution. Of the remaining claims, claims 1, 14 and 26 are independent.

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